

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10607524	CHANG ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Yabut, Diane	3734

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
606	139, 144, 153	01/04/2008	DY

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST Search -- see attached Search History, updated 03/02/2007	01/04/2008	DY

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

--	--